

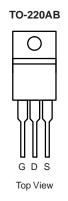
STP7NK80Z-VB Datasheet

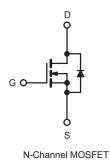
N-Channel 800V (D-S) Super Junction Power MOSFET

PRODUCT SUMMARY				
V _{DS} (V)	800			
R _{DS(on)} (Ω)	$V_{GS} = 10 V$	1.2		
Q _g (Max.) (nC)	200			
Q _{gs} (nC)	24			
Q _{gd} (nC)	110			
Configuration	Single			

FEATURES

- Dynamic dV/dt Rating
- Repetitive Avalanche Rated
- Isolated Central Mounting Hole
- · Fast Switching
- · Ease of Paralleling
- Simple Drive Requirements
- Compliant to RoHS Directive 2002/95/EC





ABSOLUTE MAXIMUM RATINGS ($T_C = 25$ °C, unless otherwise noted)						
PARAMETER			SYMBOL	LIMIT	UNIT	
Drain-Source Voltage			V _{DS}	800	V	
Gate-Source Voltage			V _{GS}	± 20		
Continuous Drain Current	V _{GS} at 10 V	$T_{C} = 25 \text{ °C}$ $T_{C} = 100 \text{ °C}$	Ι _D	5		
Continuous Drain Current				3.9	A	
Pulsed Drain Current ^a			I _{DM}	21		
Linear Derating Factor				1.5	W/°C	
Single Pulse Avalanche Energy ^b			E _{AS}	770	mJ	
Repetitive Avalanche Current ^a			I _{AR}	7.8	A	
Repetitive Avalanche Energy ^a			E _{AR}	19	mJ	
Maximum Power Dissipation	T _C =	25 °C	PD	190	W	
Peak Diode Recovery dV/dt ^c			dV/dt	2.0	V/ns	
Operating Junction and Storage Temperature Range			T _J , T _{stg}	- 55 to + 150	°C	
Soldering Recommendations (Peak Temperature)	for	10 s		300 ^d		
Mounting Torque	6-32 or M3 screw			10	lbf ∙ in	
				1.1	N · m	

Notes

a. Repetitive rating; pulse width limited by maximum junction temperature (see fig. 11). b. V_{DD} = 50 V, starting T_J = 25 °C, L = 23 mH, R_g = 25 Ω , I_{AS} = 7.8 A (see fig. 12). c. I_{SD} \leq 7.8 A, dl/dt \leq 140 A/µs, V_{DD} \leq 600 V, T_J \leq 150 °C.

d. 1.6 mm from case.

* Pb containing terminations are not RoHS compliant, exemptions may apply

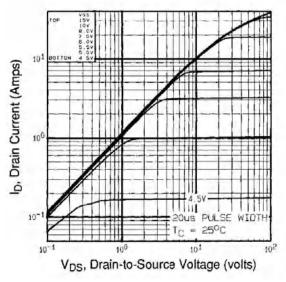


THERMAL RESISTANCE RATII	NGS							
PARAMETER	SYMBOL	TYP.	TYP. MAX.			UNIT		
Maximum Junction-to-Ambient	R _{thJA}	- 40 0.24 - - 0.65			°C/W			
Case-to-Sink, Flat, Greased Surface	R _{thCS}							
Maximum Junction-to-Case (Drain)	R _{thJC}							
	nlaan othorrui	aa natad)						
SPECIFICATIONS (T _J = 25 °C, u PARAMETER	SYMBOL	1	T CONDIT		MIN.	TYP.	MAX.	UNIT
Static	STMDOL	IES	I CONDIT		IVIIIN.	ITP.	IVIAA.	UNIT
Drain-Source Breakdown Voltage	V _{DS}	Voo	= 0 V, I _D =	250 µA	800	_	_	V
V _{DS} Temperature Coefficient	$\Delta V_{DS}/T_J$			$I_D = 1 \text{ mA}$	-	0.98	_	V/°C
Gate-Source Threshold Voltage			= V _{GS} , I _D =		2.0	-	4.0	V
Gate-Source Leakage	V _{GS(th)}	-		-	-	_	± 100	nA
Gale-Source Leakage	I _{GSS}		$V_{GS} = \pm 20 V$		-	-	± 100	ΠA
Zero Gate Voltage Drain Current	I _{DSS}	_	$V_{DS} = 800 \text{ V}, \text{ V}_{GS} = 0 \text{ V}$		-	-		μA
Drain-Source On-State Resistance		$V_{DS} = 640 \text{ V}, V_{GS} = 0 \text{ V}, T_J = 125 \text{ °C}$		-		500	0	
	R _{DS(on)}	V _{GS} = 10 V		$p = 3.7 \text{A}^{\text{b}}$	-	1.2	-	Ω
Forward Transconductance Dynamic	9fs	V _{DS} =	100 V, I _D :	= 3.7 A ⁵	5.6	-	-	S
-	C				_	2100	_	
Input Capacitance	Ciss	$V_{GS} = 0 V,$ $V_{DS} = 25 V,$ f = 1.0 MHz, see fig. 5		-	3100	-	pF	
Output Capacitance	Coss				800	-		
Reverse Transfer Capacitance	C _{rss}			-	490			
Total Gate Charge	Qg		$V_{GS} = 10 \text{ V} \qquad \begin{array}{c} I_{D} = 3.8 \text{ A}, V_{DS} = 400 \text{ V},\\ \text{see fig. 6 and } 13^{\text{b}} \end{array}$		-	-	200	nC
Gate-Source Charge	Q _{gs}	$v_{GS} = 10 V$			-	-	24	
Gate-Drain Charge	Q _{gd}				-	-	110	
Turn-On Delay Time	t _{d(on)}	$V_{DD} = 400 \text{ V}, \text{ I}_{D} = 3.8 \text{ A}, \\ \text{R}_{g} = 6.2 \ \Omega, \text{ R}_{D} = 52 \ \Omega \\ \text{see fig. 10^{b}}$		-	19	-	ns	
Rise Time	tr			-	38	-		
Turn-Off Delay Time	t _{d(off)}			-	120	-		
Fall Time	t _f			-	39	-		
Internal Drain Inductance	L _D	Between lead, 6 mm (0.25") from package and center of die contact		-	5.0	-	nH	
Internal Source Inductance	L _S			-	13	-		
Drain-Source Body Diode Characteristic	S	<u> </u>					1	
Continuous Source-Drain Diode Current	I _S	MOSFET symbol showing the integral reverse p - n junction diode		-	-	5.0	A	
Pulsed Diode Forward Current ^a	I _{SM}			-	-	21		
Body Diode Voltage	V _{SD}	T _J = 25 °C, I _S = 3.8 A, V _{GS} = 0 V ^b		-	-	1.8	V	
Body Diode Reverse Recovery Time	t _{rr}	$T_{J} = 25 \text{ °C}, I_{F} = 3.8 \text{ A},$ $dI/dt = 100 \text{ A/}\mu\text{s}^{b}$ Intrinsic turn-on time is negligible (turn		-	650	980	ns	
Body Diode Reverse Recovery Charge	Q _{rr}			-	3.8	5.7	μC	
Forward Turn-On Time	t _{on}			-on is dor				

Notes

a. Repetitive rating; pulse width limited by maximum junction temperature (see fig. 11).
b. Pulse width ≤ 300 µs; duty cycle ≤ 2 %.





TYPICAL CHARACTERISTICS (25 °C, unless otherwise noted)



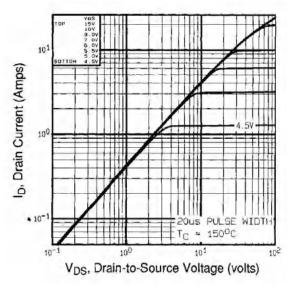


Fig. 2 - Typical Output Characteristics, T_C = 150 $^\circ C$

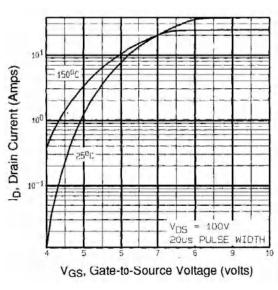


Fig. 3 - Typical Transfer Characteristics

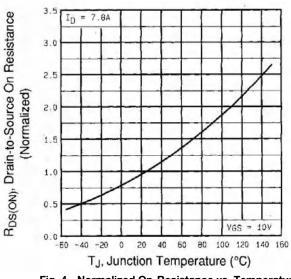


Fig. 4 - Normalized On-Resistance vs. Temperature

STP7NK80Z-VB



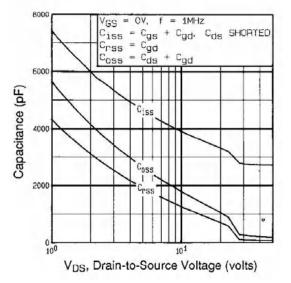


Fig. 5 - Typical Capacitance vs. Drain-to-Source Voltage



Fig. 7 - Typical Source-Drain Diode Forward Voltage

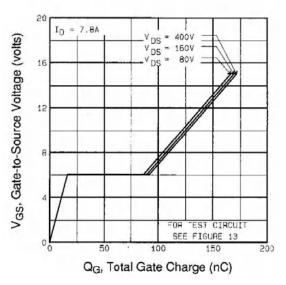
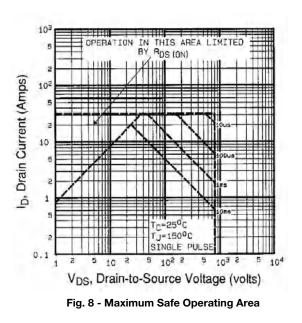


Fig. 6 - Typical Gate Charge vs. Gate-to-Source Voltage





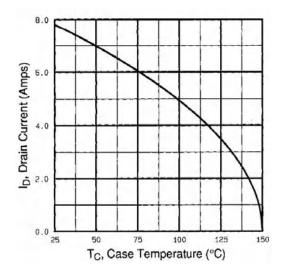


Fig. 9 - Maximum Drain Current vs. Case Temperature

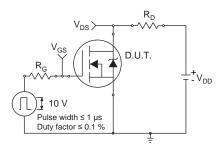


Fig. 10a - Switching Time Test Circuit

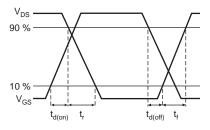


Fig. 10b - Switching Time Waveforms

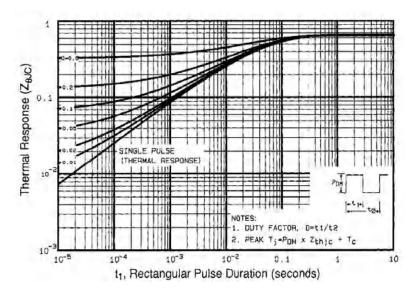


Fig. 11 - Maximum Effective Transient Thermal Impedance, Junction-to-Case



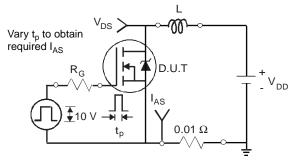


Fig. 12a - Unclamped Inductive Test Circuit

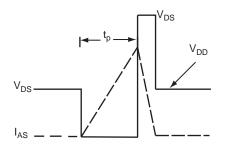


Fig. 12b - Unclamped Inductive Waveforms

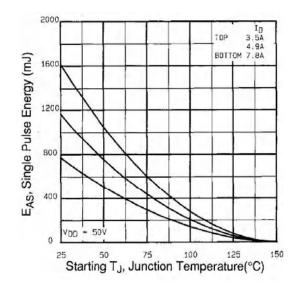


Fig. 12c - Maximum Avalanche Energy vs. Drain Current

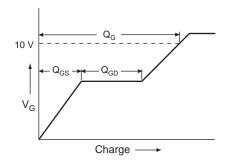


Fig. 13a - Basic Gate Charge Waveform

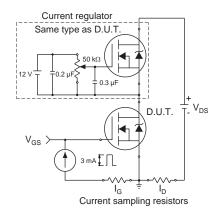
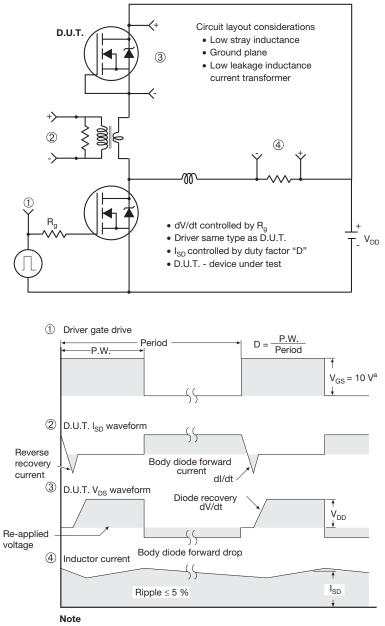


Fig. 13b - Gate Charge Test Circuit



Peak Diode Recovery dV/dt Test Circuit

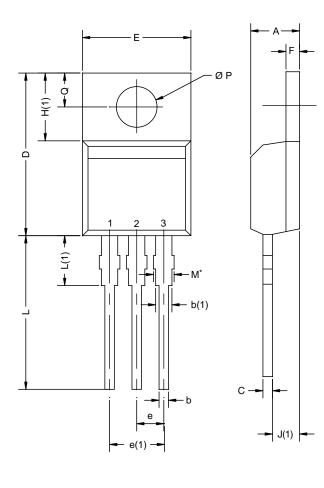


a. $V_{GS} = 5 V$ for logic level devices

Fig. 14 - For N-Channel



TO-220AB



	MILLIM	IETERS	INCHES		
DIM.	MIN.	MAX.	MIN.	MAX.	
А	4.25	4.65	0.167	0.183	
b	0.69	1.01	0.027	0.040	
b(1)	1.20	1.73	0.047	0.068	
С	0.36	0.61	0.014	0.024	
D	14.85	15.49	0.585	0.610	
E	10.04	10.51	0.395	0.414	
е	2.41	2.67	0.095	0.105	
e(1)	4.88	5.28	0.192	0.208	
F	1.14	1.40	0.045	0.055	
H(1)	6.09	6.48	0.240	0.255	
J(1)	2.41	2.92	0.095	0.115	
L	13.35	14.02	0.526	0.552	
L(1)	3.32	3.82	0.131	0.150	
ØР	3.54	3.94	0.139	0.155	
Q	2.60	3.00	0.102	0.118	
ECN: X12-0208-Rev. N, 08-Oct-12 DWG: 5471					

Notes

 * M = 1.32 mm to 1.62 mm (dimension including protrusion) Heatsink hole for HVM



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